## Notice of References Cited Application/Control No. 10/577,764 Examiner GELEK TOPGYAL Applicant(s)/Patent Under Reexamination YABUTA, TETSUTAKA Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0097985 A1	07-2002	Kaizu et al.	386/83
*	В	US-2002/0168177 A1	11-2002	Kajitani, Ichiro	386/83
*	С	US-2003/0086694 A1	05-2003	Davidsson, Marcus	386/83
*	D	US-2004/0052504 A1	03-2004	Yamada et al.	386/068
*	Е	US-2004/0105532 A1	06-2004	Nakano, Sinichiro	379/088.22
*	F	US-6,971,109 B1	11-2005	Williams et al.	719/318
*	G	US-7,076,152 B1	07-2006	Eguchi et al.	386/83
*	Н	US-7,088,952 B1	08-2006	Saito et al.	455/3.06
*	ı	US-7,212,729 B2	05-2007	Nakajima et al.	386/83
*	J	US-2007/0196078 A1	05-2007	Kunii et al.	386/083
	K	US-	1		
	Ĺ	US-	1		
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z	JP 403083243 A	04-1991	JAPAN	TSUTOMU SHIMIZU	G11B15/02, H04N5/782
	0	JP 402252154 A	10-1990	JAPAN	HISAYASU MORI	G11B15/02, H04N5/782
	Р		A			
-	σ					
4	R					
	Ø					
	-				ı C.	

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.